Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/611,422	CHUN, YOUNG-SUN		
Examiner	Art Unit		
Julian D. Huffman	2853		

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
347/19; 400/74 (Text search only, See Search history printout)	10/18/2005	JH
Stephen Meier (intended use claim interpretation)	10/18/2005	JH
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